

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1233	Jul-96	9624 A5	CARSEM	DM608597ACH	1.2μ NITRIDE	03 SOT223

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
HTC Vapor Phase
P-17812

<u>Electrical</u>	<u>Cum %</u>
233/1	0.4%
F1	

Sonoscan
P-17876

<u>Post Vapor Phase</u>
2/0

Infant / High Voltage Life
125°C, 7.0 V.
P-17877, P-18013

<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
230/0	77/0	77/0	30 Fits

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-18014

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
39/0	39/0	0.0%

Biased Moisture (HAST)
120°C/85% RH, 5.5 V.
P-18015

<u>100 Hr</u>	<u>Cum %</u>
70/0	0.0%

Autoclave
121°C/100% RH, 2 Atmos
P-18016

<u>96 Hr</u>	<u>Cum %</u>
38/0	0.0%

Failure Mode
F1: Vcc Trippt

Failure Analysis
In process, 960214